



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Ying Zhou, et al.

Serial No.: 10/696,204

Filed: October 29, 2003

For: Depositing an Oxide

§ Group Art Unit: 2812

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Examiner:

Atty. Dkt. No.: ITL.1024US (P16711)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Applicant submits the references listed on the attached form PTO 1449 together with any required copies of such references.

This statement is being filed before the receipt of a first Office action on the merits.

Please apply any charges or credits to Deposit Account 20-1504 (ITL.1024US).

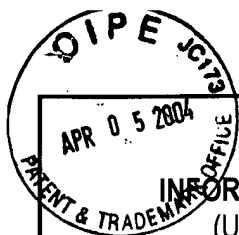
Respectfully submitted,

Date: April 2, 2004

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Date of Deposit: **April 2, 2004**
I hereby certify under 37 CFR 1.8(a) that this correspondence is being deposited with the United States Postal Service as **first class mail** with sufficient postage on the date indicated above and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Rebecca R. Ginn



INFORMATION DISCLOSURE CITATION
(Use several sheets if necessary)

ATTY DOCKET NO. ITL.1027US (P16711)	SERIAL NO. 10/696,204
APPLICANT(S): YING ZHOU, ET AL.	
FILING DATE: October 29, 2003	GROUP ART UNIT: 2812

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A.						
	B.						
	C.						
	D.						
	E.						
	F.						
	G.						
	H.						
	I.						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	J.							
	K.							
	L.							
	M.							
	N.							
	O.							

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	P.	Robert M. Wallace, "Challenges for the Characterization and Integration of High-k Gate Dielectrics," pp. 1-50, Nov. 2002, http://www.mtsc.unt.edu/lemd/Presentations/AVS%202002%20Invited%20Talk.pdf
	Q.	Gerry Lucovsky, "The Physics and Chemistry of High-k Dielectrics and their Interfaces," pp. 1-49, available on June 2003, at http://www.semtech.org/public/news/conferences/Reliability4/Documents/03_Gate_Stack_Transistor_Lucovsky.pdf
	R.	
	S.	
	T.	

EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.